Hybrid 8j66 Traveler

November 15, 1999

1 Connectivity

Repairs on shorts:

Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J66 has die: 073-045 073-046 073-047 000-000 066-028 066-031 066-036 066-037

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 8j66 classification info. Created 09:34:57 11/12/99

Hybrid 8j66 quality: fair
Chip classification: good fair fair good good good fair good
Bad channels (chip-channel): 2-31 6-118
Bad cells: none
Random bad capacitors (chip-cell-channel): 1-7-88 6-1-118 6-1-119
   6-14-119 6-2-119 6-31-119 6-34-119 6-36-119 6-38-119
Channels at pedestal needed for DCMS: 34.7 36.2 32.8 34.7 35.2 34.6 35.6 34.6
```

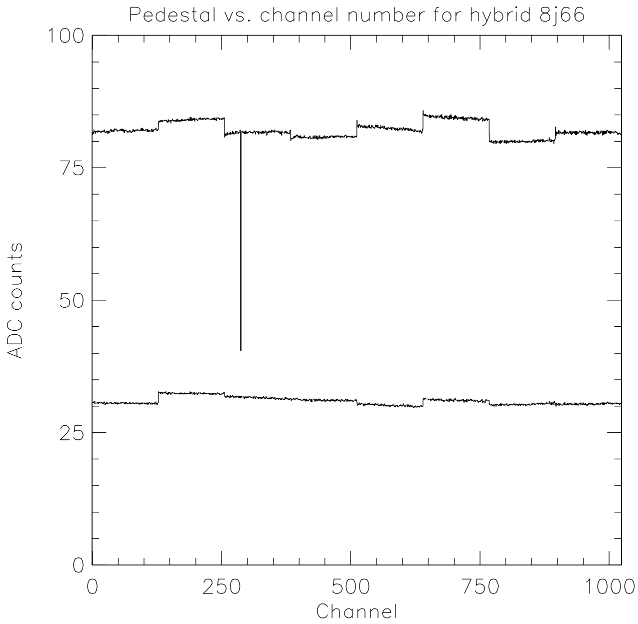
4 Comments

No comments.

5 Pedestal

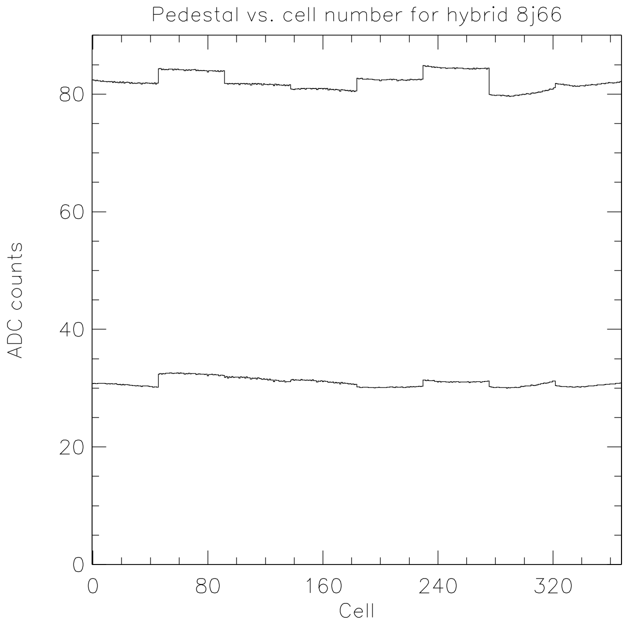
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

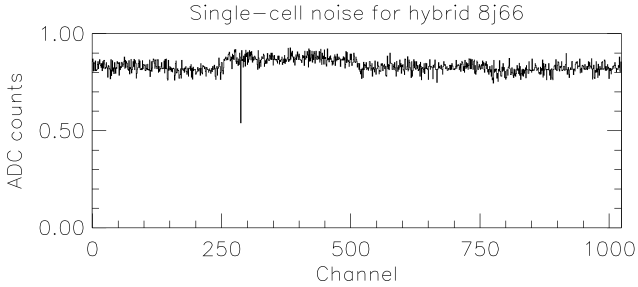
Pedestal vs. Pipeline Cell ID

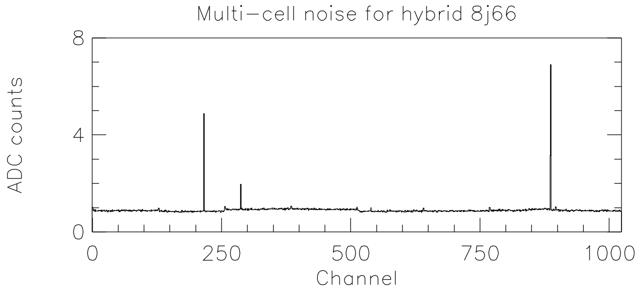


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

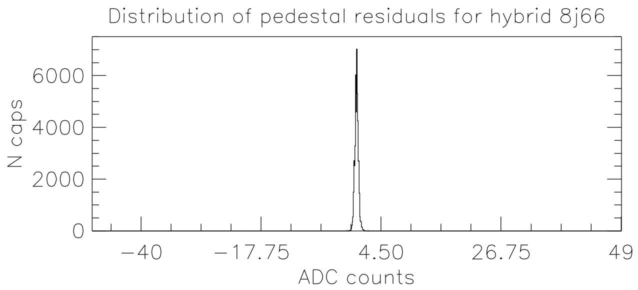
RMS Noise

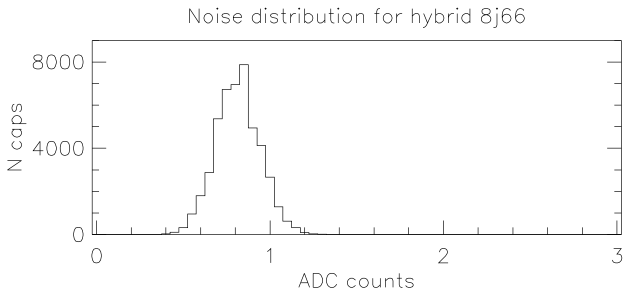




The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in